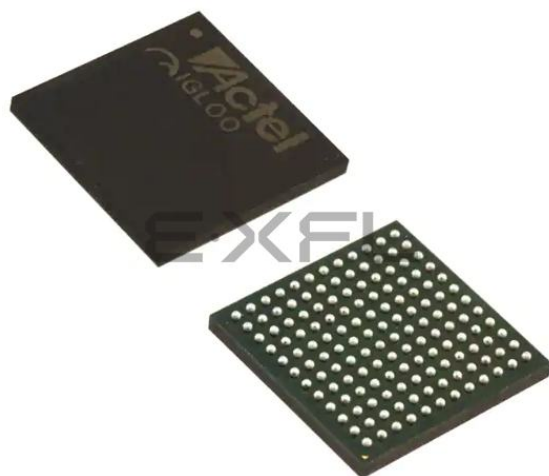




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Understanding [Embedded - FPGAs \(Field Programmable Gate Array\)](#)

Embedded - FPGAs, or Field Programmable Gate Arrays, are advanced integrated circuits that offer unparalleled flexibility and performance for digital systems. Unlike traditional fixed-function logic devices, FPGAs can be programmed and reprogrammed to execute a wide array of logical operations, enabling customized functionality tailored to specific applications. This reprogrammability allows developers to iterate designs quickly and implement complex functions without the need for custom hardware.

Applications of Embedded - FPGAs

The versatility of Embedded - FPGAs makes them indispensable in numerous fields. In telecommunications.

Details

Product Status	Active
Number of LABs/CLBs	768
Number of Logic Elements/Cells	-
Total RAM Bits	-
Number of I/O	111
Number of Gates	12000
Voltage - Supply	3V ~ 3.6V, 4.75V ~ 5.25V
Mounting Type	Surface Mount
Operating Temperature	-40°C ~ 85°C (TA)
Package / Case	144-LBGA
Supplier Device Package	144-FPBGA (13x13)
Purchase URL	https://www.e-xfl.com/product-detail/microchip-technology/a54sx08-2fgg144i

Boundary Scan Testing (BST)

All SX devices are IEEE 1149.1 compliant. SX devices offer superior diagnostic and testing capabilities by providing Boundary Scan Testing (BST) and probing capabilities. These functions are controlled through the special test pins in conjunction with the program fuse. The functionality of each pin is described in Table 1-2. In the dedicated test mode, TCK, TDI, and TDO are dedicated pins and cannot be used as regular I/Os. In flexible mode, TMS should be set HIGH through a pull-up resistor of 10 kΩ. TMS can be pulled LOW to initiate the test sequence.

The program fuse determines whether the device is in dedicated or flexible mode. The default (fuse not blown) is flexible mode.

Table 1-2 • Boundary Scan Pin Functionality

Program Fuse Blown (Dedicated Test Mode)	Program Fuse Not Blown (Flexible Mode)
TCK, TDI, TDO are dedicated BST pins.	TCK, TDI, TDO are flexible and may be used as I/Os.
No need for pull-up resistor for TMS	Use a pull-up resistor of 10 kΩ on TMS.

Dedicated Test Mode

In Dedicated mode, all JTAG pins are reserved for BST; designers cannot use them as regular I/Os. An internal pull-up resistor is automatically enabled on both TMS and TDI pins, and the TMS pin will function as defined in the IEEE 1149.1 (JTAG) specification.

To select Dedicated mode, users need to reserve the JTAG pins in Actel's Designer software by checking the "Reserve JTAG" box in "Device Selection Wizard" (Figure 1-7). JTAG pins comply with LVTTTL/TTL I/O specification regardless of whether they are used as a user I/O or a JTAG I/O. Refer to the Table 1-5 on page 1-8 for detailed specifications.

Development Tool Support

The SX family of FPGAs is fully supported by both the Actel Libero® Integrated Design Environment (IDE) and Designer FPGA Development software. Actel Libero IDE is a design management environment, seamlessly integrating design tools while guiding the user through the design flow, managing all design and log files, and passing necessary design data among tools. Libero IDE allows users to integrate both schematic and HDL synthesis into a single flow and verify the entire design in a single environment. Libero IDE includes Synplify® for Actel from Synplicity®, ViewDraw® for Actel from Mentor Graphics®, ModelSim® HDL Simulator from Mentor Graphics, WaveFormer Lite™ from SynaptiCAD™, and Designer software from Actel. Refer to the Libero IDE flow diagram (located on the Actel website) for more information.

Actel Designer software is a place-and-route tool and provides a comprehensive suite of backend support tools for FPGA development. The Designer software includes timing-driven place-and-route, and a world-class integrated static timing analyzer and constraints editor. With the Designer software, a user can select and lock package pins while only minimally impacting the results of place-and-route. Additionally, the back-annotation flow is compatible with all the major simulators, and the simulation results can be cross-probed with Silicon Explorer II, Actel integrated verification and logic analysis tool. Another tool included in the Designer software is the SmartGen core generator, which easily creates popular and commonly used logic functions for implementation into your schematic or HDL design. Actel Designer software is compatible with the most popular FPGA design entry and verification tools from companies such as Mentor Graphics, Synplicity, Synopsys®, and Cadence® Design Systems. The Designer software is available for both the Windows® and UNIX® operating systems.

Probe Circuit Control Pins

The Silicon Explorer II tool uses the boundary scan ports (TDI, TCK, TMS, and TDO) to select the desired nets for verification. The selected internal nets are assigned to the PRA/PRB pins for observation. Figure 1-8 on page 1-7 illustrates the interconnection between Silicon Explorer II and the FPGA to perform in-circuit verification.

Design Considerations

The TDI, TCK, TDO, PRA, and PRB pins should not be used as input or bidirectional ports. Because these pins are active during probing, critical signals input through these pins are not available while probing. In addition, the Security Fuse should not be programmed because doing so disables the Probe Circuitry.

Figure 1-7 • Device Selection Wizard

Table 1-4 • Recommended Operating Conditions

Parameter	Commercial	Industrial	Military	Units
Temperature Range*	0 to + 70	–40 to + 85	–55 to +125	°C
3.3 V Power Supply Tolerance	±10	±10	±10	%V _{CC}
5.0 V Power Supply Tolerance	±5	±10	±10	%V _{CC}

Note: *Ambient temperature (T_A) is used for commercial and industrial; case temperature (T_C) is used for military.

Table 1-5 • Electrical Specifications

Symbol	Parameter	Commercial		Industrial		Units
		Min.	Max.	Min.	Max.	
V _{OH}	(I _{OH} = –20 μ A) (CMOS) (I _{OH} = –8 mA) (TTL) (I _{OH} = –6 mA) (TTL)	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	(V _{CCI} – 0.1) 2.4	V _{CCI} V _{CCI}	V
V _{OL}	(I _{OL} = 20 μ A) (CMOS) (I _{OL} = 12 mA) (TTL) (I _{OL} = 8 mA) (TTL)		0.10 0.50		0.50	V
V _{IL}			0.8		0.8	V
V _{IH}		2.0		2.0		V
t _R , t _F	Input Transition Time t _R , t _F		50		50	ns
C _{IO}	C _{IO} I/O Capacitance		10		10	pF
I _{CC}	Standby Current, I _{CC}		4.0		4.0	mA
I _{CC(D)}	I _{CC(D)} I _{Dynamic} V _{CC} Supply Current	See "Evaluating Power in SX Devices" on page 1-16.				

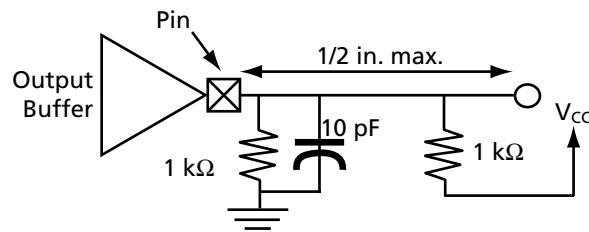
A54SX16P AC Specifications for (PCI Operation)

Table 1-7 • A54SX16P AC Specifications for (PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 1.4^1$	-44		mA
		$1.4 \leq V_{OUT} < 2.4^1, ^2$	$-44 + (V_{OUT} - 1.4)/0.024$		mA
		$3.1 < V_{OUT} < V_{CC}^{1, ^3}$		EQ 1-1 on page 1-11	
	(Test Point)	$V_{OUT} = 3.1^3$		-142	mA
$I_{OL(AC)}$	Switching Current High	$V_{OUT} \geq 2.2^1$	95		mA
		$2.2 > V_{OUT} > 0.55^1$	$V_{OUT}/0.023$		
		$0.71 > V_{OUT} > 0^{1, ^3}$		EQ 1-2 on page 1-11	mA
	(Test Point)	$V_{OUT} = 0.71^3$		206	mA
I_{CL}	Low Clamp Current	$-5 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate	0.4 V to 2.4 V load ⁴	1	5	V/ns
$slew_F$	Output Fall Slew Rate	2.4 V to 0.4 V load ⁴	1	5	V/ns

Notes:

1. Refer to the *V_I* curves in Figure 1-9 on page 1-11. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half-size output drivers may be used on these signals. This specification does not apply to CLK and RST#, which are system outputs. "Switching Current High" specifications are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD#, which are open drain outputs.
2. Note that this segment of the minimum current curve is drawn from the AC drive point directly to the DC drive point rather than toward the voltage rail (as is done in the pull-down curve). This difference is intended to allow for an optional N-channel pull-up.
3. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maxima (A and B) are provided with the respective diagrams in Figure 1-9 on page 1-11. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
4. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per revision 2.0 of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is now required (the maximum is no longer simply a guideline). Since adherence to the maximum slew rate was not required prior to revision 2.1 of the specification, there may be components in the market for some time that have faster edge rates; therefore, motherboard designers must bear in mind that rise and fall times faster than this specification could occur, and should ensure that signal integrity modeling accounts for this. Rise slew rate does not apply to open drain outputs.



A54SX16P DC Specifications (3.3 V PCI Operation)

Table 1-8 • A54SX16P DC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
V_{CCA}	Supply Voltage for Array		3.0	3.6	V
V_{CCR}	Supply Voltage required for Internal Biasing		3.0	3.6	V
V_{CCI}	Supply Voltage for I/Os		3.0	3.6	V
V_{IH}	Input High Voltage		$0.5V_{CC}$	$V_{CC} + 0.5$	V
V_{IL}	Input Low Voltage		-0.5	$0.3V_{CC}$	V
I_{PU}	Input Pull-up Voltage ¹		$0.7V_{CC}$		V
I_{IL}	Input Leakage Current ²	$0 < V_{IN} < V_{CC}$		± 10	μA
V_{OH}	Output High Voltage	$I_{OUT} = -500 \mu A$	$0.9V_{CC}$		V
V_{OL}	Output Low Voltage	$I_{OUT} = 1500 \mu A$		$0.1V_{CC}$	V
C_{IN}	Input Pin Capacitance ³			10	pF
C_{CLK}	CLK Pin Capacitance		5	12	pF
C_{IDSEL}	IDSEL Pin Capacitance ⁴			8	pF

Notes:

1. This specification should be guaranteed by design. It is the minimum voltage to which pull-up resistors are calculated to pull a floated network. Applications sensitive to static power utilization should assure that the input buffer is conducting minimum current at this input voltage.
2. Input leakage currents include hi-Z output leakage for all bidirectional buffers with tristate outputs.
3. Absolute maximum pin capacitance for a PCI input is 10 pF (except for CLK).
4. Lower capacitance on this input-only pin allows for non-resistive coupling to AD[xx].

A54SX16P AC Specifications (3.3 V PCI Operation)

Table 1-9 • A54SX16P AC Specifications (3.3 V PCI Operation)

Symbol	Parameter	Condition	Min.	Max.	Units
$I_{OH(AC)}$	Switching Current High	$0 < V_{OUT} \leq 0.3V_{CC}^1$			mA
		$0.3V_{CC} \leq V_{OUT} < 0.9V_{CC}^1$	$-12V_{CC}$		mA
		$0.7V_{CC} < V_{OUT} < V_{CC}^{1,2}$	$-17.1 + (V_{CC} - V_{OUT})$	EQ 1-3 on page 1-14	
	(Test Point)	$V_{OUT} = 0.7V_{CC}^2$		$-32V_{CC}$	mA
$I_{OL(AC)}$	Switching Current High	$V_{CC} > V_{OUT} \geq 0.6V_{CC}^1$			mA
		$0.6V_{CC} > V_{OUT} > 0.1V_{CC}^1$	$16V_{CC}$		mA
		$0.18V_{CC} > V_{OUT} > 0^{1,2}$	$26.7V_{OUT}$	EQ 1-4 on page 1-14	mA
	(Test Point)	$V_{OUT} = 0.18V_{CC}^2$		$38V_{CC}$	
I_{CL}	Low Clamp Current	$-3 < V_{IN} \leq -1$	$-25 + (V_{IN} + 1)/0.015$		mA
I_{CH}	High Clamp Current	$-3 < V_{IN} \leq -1$	$25 + (V_{IN} - V_{OUT} - 1)/0.015$		mA
$slew_R$	Output Rise Slew Rate ³	0.2V _{CC} to 0.6V _{CC} load	1	4	V/ns
$slew_F$	Output Fall Slew Rate ³	0.6V _{CC} to 0.2V _{CC} load	1	4	V/ns

Notes:

1. Refer to the V/I curves in Figure 1-10 on page 1-14. Switching current characteristics for REQ# and GNT# are permitted to be one half of that specified here; i.e., half size output drivers may be used on these signals. This specification does not apply to CLK and RST# which are system outputs. "Switching Current High" specification are not relevant to SERR#, INTA#, INTB#, INTC#, and INTD# which are open drain outputs.
2. Maximum current requirements must be met as drivers pull beyond the last step voltage. Equations defining these maximums (C and D) are provided with the respective diagrams in Figure 1-10 on page 1-14. The equation defined maxima should be met by design. In order to facilitate component testing, a maximum current test point is defined for each side of the output driver.
3. This parameter is to be interpreted as the cumulative edge rate across the specified range, rather than the instantaneous rate at any point within the transition range. The specified load (diagram below) is optional; i.e., the designer may elect to meet this parameter with an unloaded output per the latest revision of the PCI Local Bus Specification. However, adherence to both maximum and minimum parameters is required (the maximum is no longer simply a guideline). Rise slew rate does not apply to open drain outputs.

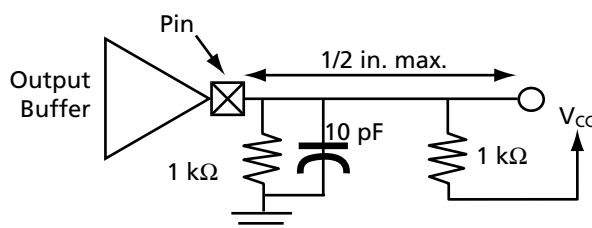


Figure 1-10 shows the 3.3 V PCI V/I curve and the minimum and maximum PCI drive characteristics of the A54SX16P device.

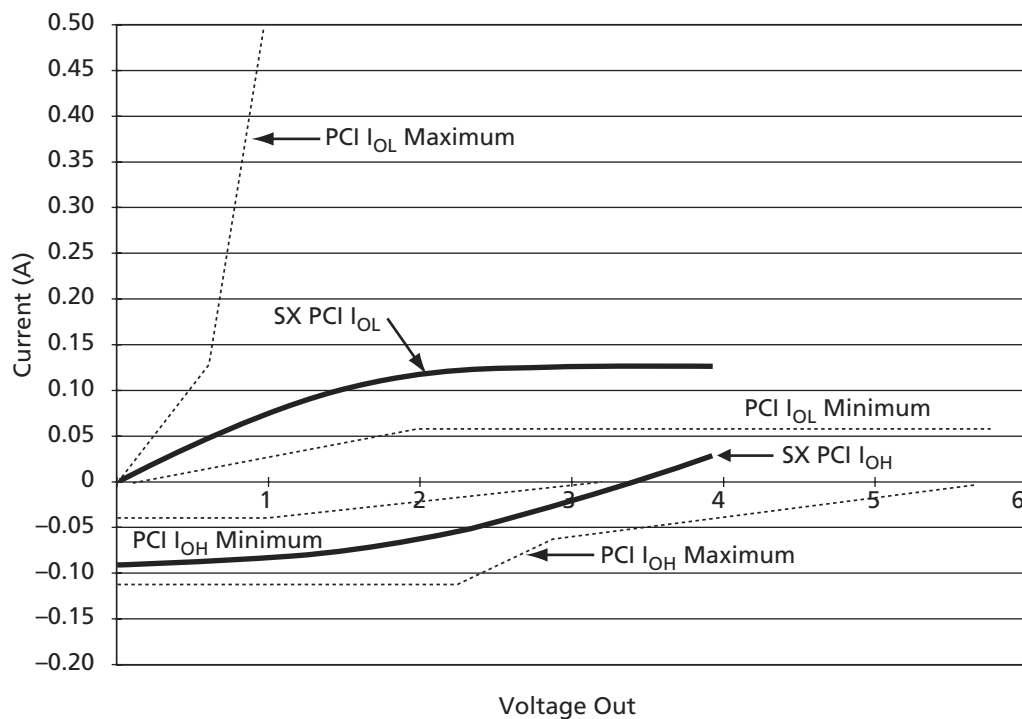


Figure 1-10 • 3.3 V PCI Curve for A54SX16P Device

$$I_{OH} = (98.0/V_{CC}) \times (V_{OUT} - V_{CC}) \times (V_{OUT} + 0.4V_{CC})$$

for $V_{CC} > V_{OUT} > 0.7 V_{CC}$

EQ 1-3

$$I_{OL} = (256/V_{CC}) \times V_{OUT} \times (V_{CC} - V_{OUT})$$

for $0 V < V_{OUT} < 0.18 V_{CC}$

EQ 1-4

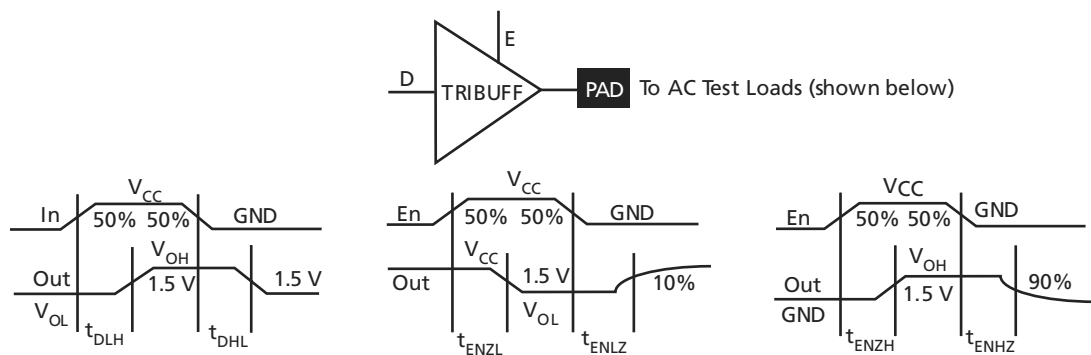


Figure 1-13 • Output Buffer Delays

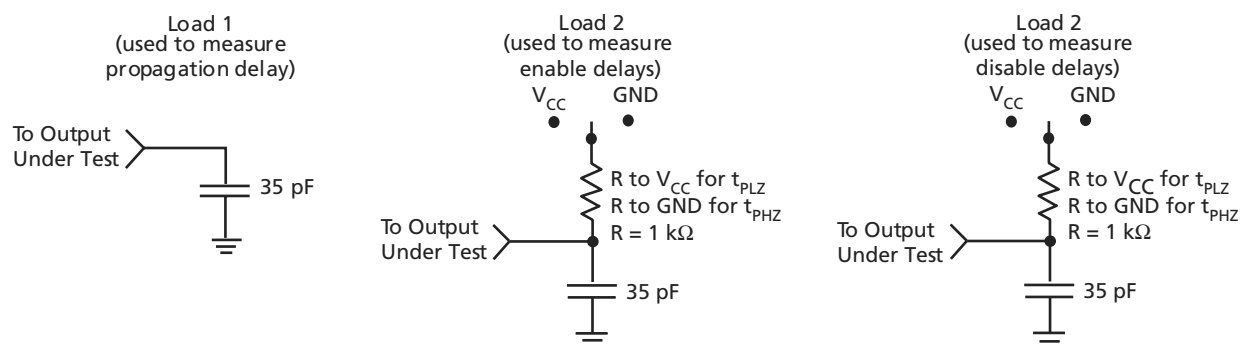


Figure 1-14 • AC Test Loads

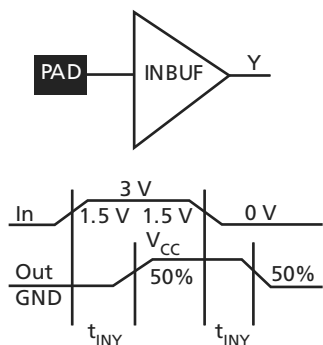


Figure 1-15 • Input Buffer Delays

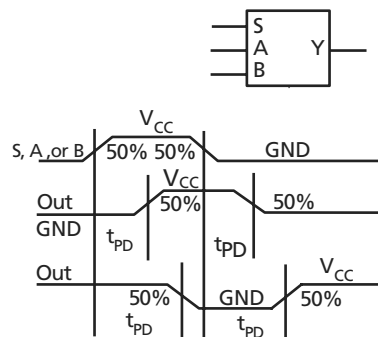


Figure 1-16 • C-Cell Delays

Register Cell Timing Characteristics

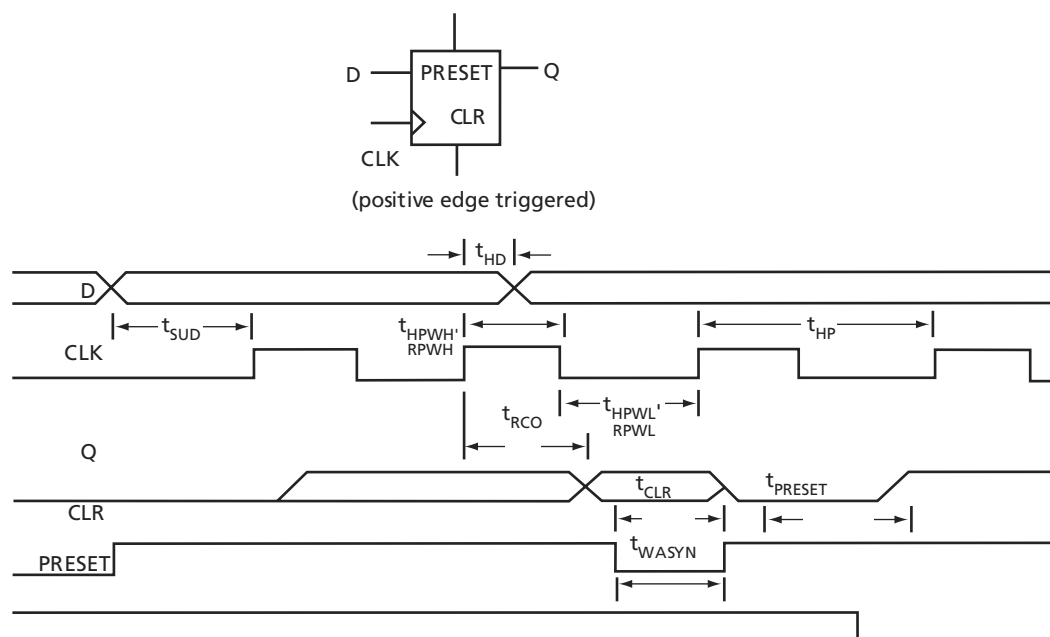


Figure 1-17 • Flip-Flops

Timing Characteristics

Timing characteristics for SX devices fall into three categories: family-dependent, device-dependent, and design-dependent. The input and output buffer characteristics are common to all SX family members. Internal routing delays are device-dependent. Design dependency means actual delays are not determined until after placement and routing of the user's design is complete. Delay values may then be determined by using the DirectTime Analyzer utility or performing simulation with post-layout delays.

Critical Nets and Typical Nets

Propagation delays are expressed only for typical nets, which are used for initial design performance evaluation. Critical net delays can then be applied to the most time-critical paths. Critical nets are determined by net property assignment prior to placement and routing. Up to 6% of the nets in a design may be designated as critical, while 90% of the nets in a design are typical.

Long Tracks

Some nets in the design use long tracks. Long tracks are special routing resources that span multiple rows, columns, or modules. Long tracks employ three and sometimes five antifuse connections. This increases capacitance and resistance, resulting in longer net delays for macros connected to long tracks. Typically up to 6 percent of nets in a fully utilized device require long tracks. Long tracks contribute approximately 4 ns to 8.4 ns delay. This additional delay is represented statistically in higher fanout ($FO = 24$) routing delays in the datasheet specifications section.

Timing Derating

SX devices are manufactured in a CMOS process. Therefore, device performance varies according to temperature, voltage, and process variations. Minimum timing parameters reflect maximum operating voltage, minimum operating temperature, and best-case processing. Maximum timing parameters reflect minimum operating voltage, maximum operating temperature, and worst-case processing.

Table 1-18 • A54SX16 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.2		1.4		1.5		1.8		ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.2		1.4		1.6		1.9		ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew	0.2		0.2		0.3		0.3		ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	1.6		1.8		2.1		2.5		ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)	1.8		2.0		2.3		2.7		ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	1.8		2.1		2.5		2.8		ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	1.8		2.1		2.4		2.8		ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.0		2.2		2.5		3.0		ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)	0.5		0.5		0.5		0.7		ns
t _{RCKSW}	Maximum Skew (50% load)	0.5		0.6		0.7		0.8		ns
t _{RCKSW}	Maximum Skew (100% load)	0.5		0.6		0.7		0.8		ns
TTL Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

Notes:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} , the loading is 5 pF.

Table 1-19 • A54SX16P Timing Characteristics (Continued)

(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
TTL/PCI Output Module Timing										
t _{DLH}	Data-to-Pad LOW to HIGH	1.5		1.7		2.0		2.3		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.9		2.2		2.4		2.9		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.3		2.6		3.0		3.5		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.5		1.7		1.9		2.3		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.7		3.1		3.5		4.1		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.9		3.3		3.7		4.4		ns
PCI Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.8		2.0		2.3		2.7		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.7		2.0		2.2		2.6		ns
t _{ENZL}	Enable-to-Pad, Z to L	0.8		1.0		1.1		1.3		ns
t _{ENZH}	Enable-to-Pad, Z to H	1.2		1.2		1.5		1.8		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.0		1.1		1.3		1.5		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.1		1.3		1.5		1.7		ns
TTL Output Module Timing										
t _{DLH}	Data-to-Pad LOW to HIGH	2.1		2.5		2.8		3.3		ns
t _{DHL}	Data-to-Pad HIGH to LOW	2.0		2.3		2.6		3.1		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.5		2.9		3.2		3.8		ns
t _{ENZH}	Enable-to-Pad, Z to H	3.0		3.5		3.9		4.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	2.3		2.7		3.1		3.6		ns
t _{ENHZ}	Enable-to-Pad, H to Z	2.9		3.3		3.7		4.4		ns

Note:

1. For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
2. Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
3. Delays based on 10 pF loading.

A54SX32 Timing Characteristics

Table 1-20 • A54SX32 Timing Characteristics
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
C-Cell Propagation Delays ¹										
t _{PD}	Internal Array Module	0.6		0.7		0.8		0.9		ns
Predicted Routing Delays ²										
t _{DC}	FO = 1 Routing Delay, Direct Connect	0.1		0.1		0.1		0.1		ns
t _{FC}	FO = 1 Routing Delay, Fast Connect	0.3		0.4		0.4		0.5		ns
t _{RD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{RD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{RD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{RD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{RD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{RD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns
R-Cell Timing										
t _{RCO}	Sequential Clock-to-Q	0.8		1.1		1.3		1.4		ns
t _{CLR}	Asynchronous Clear-to-Q	0.5		0.6		0.7		0.8		ns
t _{PRESET}	Asynchronous Preset-to-Q	0.7		0.8		0.9		1.0		ns
t _{SUD}	Flip-Flop Data Input Set-Up	0.5		0.6		0.7		0.8		ns
t _{HD}	Flip-Flop Data Input Hold	0.0		0.0		0.0		0.0		ns
t _{WASYN}	Asynchronous Pulse Width	1.4		1.6		1.8		2.1		ns
Input Module Propagation Delays										
t _{INYH}	Input Data Pad-to-Y HIGH	1.5		1.7		1.9		2.2		ns
t _{INYL}	Input Data Pad-to-Y LOW	1.5		1.7		1.9		2.2		ns
Predicted Input Routing Delays ²										
t _{IRD1}	FO = 1 Routing Delay	0.3		0.4		0.4		0.5		ns
t _{IRD2}	FO = 2 Routing Delay	0.7		0.8		0.9		1.0		ns
t _{IRD3}	FO = 3 Routing Delay	1.0		1.2		1.4		1.6		ns
t _{IRD4}	FO = 4 Routing Delay	1.4		1.6		1.8		2.1		ns
t _{IRD8}	FO = 8 Routing Delay	2.7		3.1		3.5		4.1		ns
t _{IRD12}	FO = 12 Routing Delay	4.0		4.7		5.3		6.2		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.

Table 1-20 • A54SX32 Timing Characteristics (Continued)
(Worst-Case Commercial Conditions, $V_{CCR} = 4.75\text{ V}$, $V_{CCA}, V_{CCI} = 3.0\text{ V}$, $T_J = 70^\circ\text{C}$)

Parameter	Description	'-3' Speed		'-2' Speed		'-1' Speed		'Std' Speed		Units
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	
Dedicated (Hardwired) Array Clock Network										
t _{HCKH}	Input LOW to HIGH (pad to R-Cell input)	1.9		2.1		2.4		2.8		ns
t _{HCKL}	Input HIGH to LOW (pad to R-Cell input)	1.9		2.1		2.4		2.8		ns
t _{HPWH}	Minimum Pulse Width HIGH	1.4		1.6		1.8		2.1		ns
t _{HPWL}	Minimum Pulse Width LOW	1.4		1.6		1.8		2.1		ns
t _{HCKSW}	Maximum Skew	0.3		0.4		0.4		0.5		ns
t _{HP}	Minimum Period	2.7		3.1		3.6		4.2		ns
f _{HMAX}	Maximum Frequency	350		320		280		240		MHz
Routed Array Clock Networks										
t _{RCKH}	Input LOW to HIGH (light load) (pad to R-Cell input)	2.4		2.7		3.0		3.5		ns
t _{RCKL}	Input HIGH to LOW (light load) (pad to R-Cell input)	2.4		2.7		3.1		3.6		ns
t _{RCKH}	Input LOW to HIGH (50% load) (pad to R-Cell input)	2.7		3.0		3.5		4.1		ns
t _{RCKL}	Input HIGH to LOW (50% load) (pad to R-Cell input)	2.7		3.1		3.6		4.2		ns
t _{RCKH}	Input LOW to HIGH (100% load) (pad to R-Cell input)	2.7		3.1		3.5		4.1		ns
t _{RCKL}	Input HIGH to LOW (100% load) (pad to R-Cell input)	2.8		3.2		3.6		4.3		ns
t _{RPWH}	Min. Pulse Width HIGH	2.1		2.4		2.7		3.2		ns
t _{RPWL}	Min. Pulse Width LOW	2.1		2.4		2.7		3.2		ns
t _{RCKSW}	Maximum Skew (light load)	0.85		0.98		1.1		1.3		ns
t _{RCKSW}	Maximum Skew (50% load)	1.23		1.4		1.6		1.9		ns
t _{RCKSW}	Maximum Skew (100% load)	1.30		1.5		1.7		2.0		ns
TTL Output Module Timing ³										
t _{DLH}	Data-to-Pad LOW to HIGH	1.6		1.9		2.1		2.5		ns
t _{DHL}	Data-to-Pad HIGH to LOW	1.6		1.9		2.1		2.5		ns
t _{ENZL}	Enable-to-Pad, Z to L	2.1		2.4		2.8		3.2		ns
t _{ENZH}	Enable-to-Pad, Z to H	2.3		2.7		3.1		3.6		ns
t _{ENLZ}	Enable-to-Pad, L to Z	1.4		1.7		1.9		2.2		ns
t _{ENHZ}	Enable-to-Pad, H to Z	1.3		1.5		1.7		2.0		ns

Note:

- For dual-module macros, use $t_{PD} + t_{RD1} + t_{PDn}$, $t_{RCO} + t_{RD1} + t_{PDn}$, or $t_{PD1} + t_{RD1} + t_{SUD}$, whichever is appropriate.
- Routing delays are for typical designs across worst-case operating conditions. These parameters should be used for estimating device performance. Post-route timing analysis or simulation is required to determine actual worst-case performance. Post-route timing is based on actual routing delay measurements performed on the device prior to shipment.
- Delays based on 35 pF loading, except t_{ENZL} and t_{ENZH} . For t_{ENZL} and t_{ENZH} the loading is 5 pF.

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
145	V _{CCA}	V _{CCA}	V _{CCA}
146	GND	GND	GND
147	I/O	I/O	I/O
148	V _{CCI}	V _{CCI}	V _{CCI}
149	I/O	I/O	I/O
150	I/O	I/O	I/O
151	I/O	I/O	I/O
152	I/O	I/O	I/O
153	I/O	I/O	I/O
154	I/O	I/O	I/O
155	NC	I/O	I/O
156	NC	I/O	I/O
157	GND	GND	GND
158	I/O	I/O	I/O
159	I/O	I/O	I/O
160	I/O	I/O	I/O
161	I/O	I/O	I/O
162	I/O	I/O	I/O
163	I/O	I/O	I/O
164	V _{CCI}	V _{CCI}	V _{CCI}
165	I/O	I/O	I/O
166	I/O	I/O	I/O
167	NC	I/O	I/O
168	I/O	I/O	I/O
169	I/O	I/O	I/O
170	NC	I/O	I/O
171	I/O	I/O	I/O
172	I/O	I/O	I/O
173	NC	I/O	I/O
174	I/O	I/O	I/O
175	I/O	I/O	I/O
176	NC	I/O	I/O
177	I/O	I/O	I/O
178	I/O	I/O	I/O
179	I/O	I/O	I/O
180	CLKA	CLKA	CLKA

208-Pin PQFP			
Pin Number	A54SX08 Function	A54SX16, A54SX16P Function	A54SX32 Function
181	CLKB	CLKB	CLKB
182	V _{CCR}	V _{CCR}	V _{CCR}
183	GND	GND	GND
184	V _{CCA}	V _{CCA}	V _{CCA}
185	GND	GND	GND
186	PRA, I/O	PRA, I/O	PRA, I/O
187	I/O	I/O	I/O
188	I/O	I/O	I/O
189	NC	I/O	I/O
190	I/O	I/O	I/O
191	I/O	I/O	I/O
192	NC	I/O	I/O
193	I/O	I/O	I/O
194	I/O	I/O	I/O
195	NC	I/O	I/O
196	I/O	I/O	I/O
197	I/O	I/O	I/O
198	NC	I/O	I/O
199	I/O	I/O	I/O
200	I/O	I/O	I/O
201	V _{CCI}	V _{CCI}	V _{CCI}
202	NC	I/O	I/O
203	NC	I/O	I/O
204	I/O	I/O	I/O
205	NC	I/O	I/O
206	I/O	I/O	I/O
207	I/O	I/O	I/O
208	TCK, I/O	TCK, I/O	TCK, I/O

Note: * Note that Pin 65 in the A54SX32—PQ208 is a no connect (NC).

144-Pin TQFP

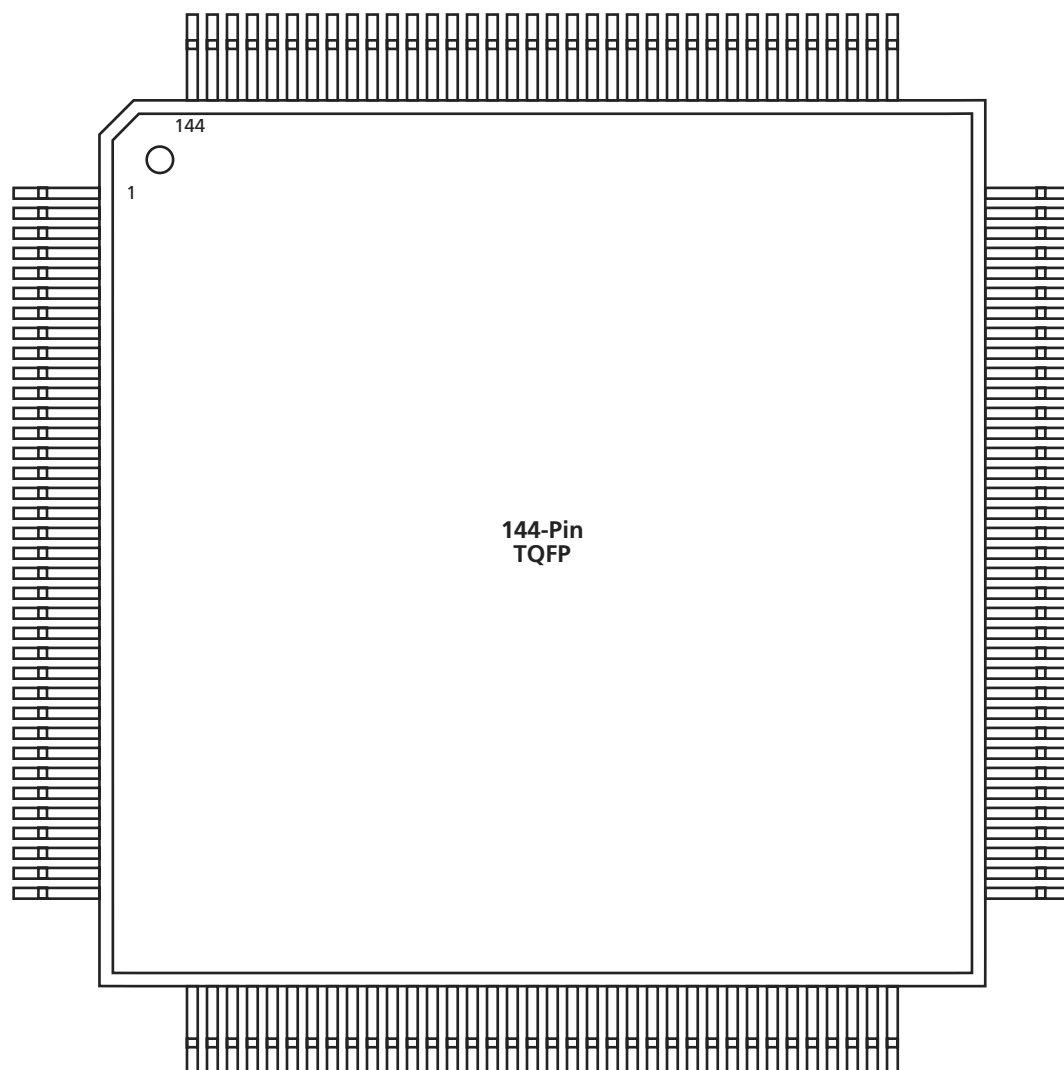


Figure 2-3 • 144-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
1	GND	GND	GND
2	TDI, I/O	TDI, I/O	TDI, I/O
3	I/O	I/O	I/O
4	I/O	I/O	I/O
5	I/O	I/O	I/O
6	I/O	I/O	I/O
7	I/O	I/O	I/O
8	I/O	I/O	I/O
9	TMS	TMS	TMS
10	V _{CCI}	V _{CCI}	V _{CCI}
11	GND	GND	GND
12	I/O	I/O	I/O
13	I/O	I/O	I/O
14	I/O	I/O	I/O
15	I/O	I/O	I/O
16	I/O	I/O	I/O
17	I/O	I/O	I/O
18	I/O	I/O	I/O
19	V _{CCR}	V _{CCR}	V _{CCR}
20	V _{CCA}	V _{CCA}	V _{CCA}
21	I/O	I/O	I/O
22	I/O	I/O	I/O
23	I/O	I/O	I/O
24	I/O	I/O	I/O
25	I/O	I/O	I/O
26	I/O	I/O	I/O
27	I/O	I/O	I/O
28	GND	GND	GND
29	V _{CCI}	V _{CCI}	V _{CCI}
30	V _{CCA}	V _{CCA}	V _{CCA}
31	I/O	I/O	I/O
32	I/O	I/O	I/O
33	I/O	I/O	I/O
34	I/O	I/O	I/O
35	I/O	I/O	I/O
36	GND	GND	GND

144-Pin TQFP			
Pin Number	A54SX08 Function	A54SX16P Function	A54SX32 Function
37	I/O	I/O	I/O
38	I/O	I/O	I/O
39	I/O	I/O	I/O
40	I/O	I/O	I/O
41	I/O	I/O	I/O
42	I/O	I/O	I/O
43	I/O	I/O	I/O
44	V _{CCI}	V _{CCI}	V _{CCI}
45	I/O	I/O	I/O
46	I/O	I/O	I/O
47	I/O	I/O	I/O
48	I/O	I/O	I/O
49	I/O	I/O	I/O
50	I/O	I/O	I/O
51	I/O	I/O	I/O
52	I/O	I/O	I/O
53	I/O	I/O	I/O
54	PRB, I/O	PRB, I/O	PRB, I/O
55	I/O	I/O	I/O
56	V _{CCA}	V _{CCA}	V _{CCA}
57	GND	GND	GND
58	V _{CCR}	V _{CCR}	V _{CCR}
59	I/O	I/O	I/O
60	HCLK	HCLK	HCLK
61	I/O	I/O	I/O
62	I/O	I/O	I/O
63	I/O	I/O	I/O
64	I/O	I/O	I/O
65	I/O	I/O	I/O
66	I/O	I/O	I/O
67	I/O	I/O	I/O
68	V _{CCI}	V _{CCI}	V _{CCI}
69	I/O	I/O	I/O
70	I/O	I/O	I/O
71	TDO, I/O	TDO, I/O	TDO, I/O
72	I/O	I/O	I/O

176-Pin TQFP

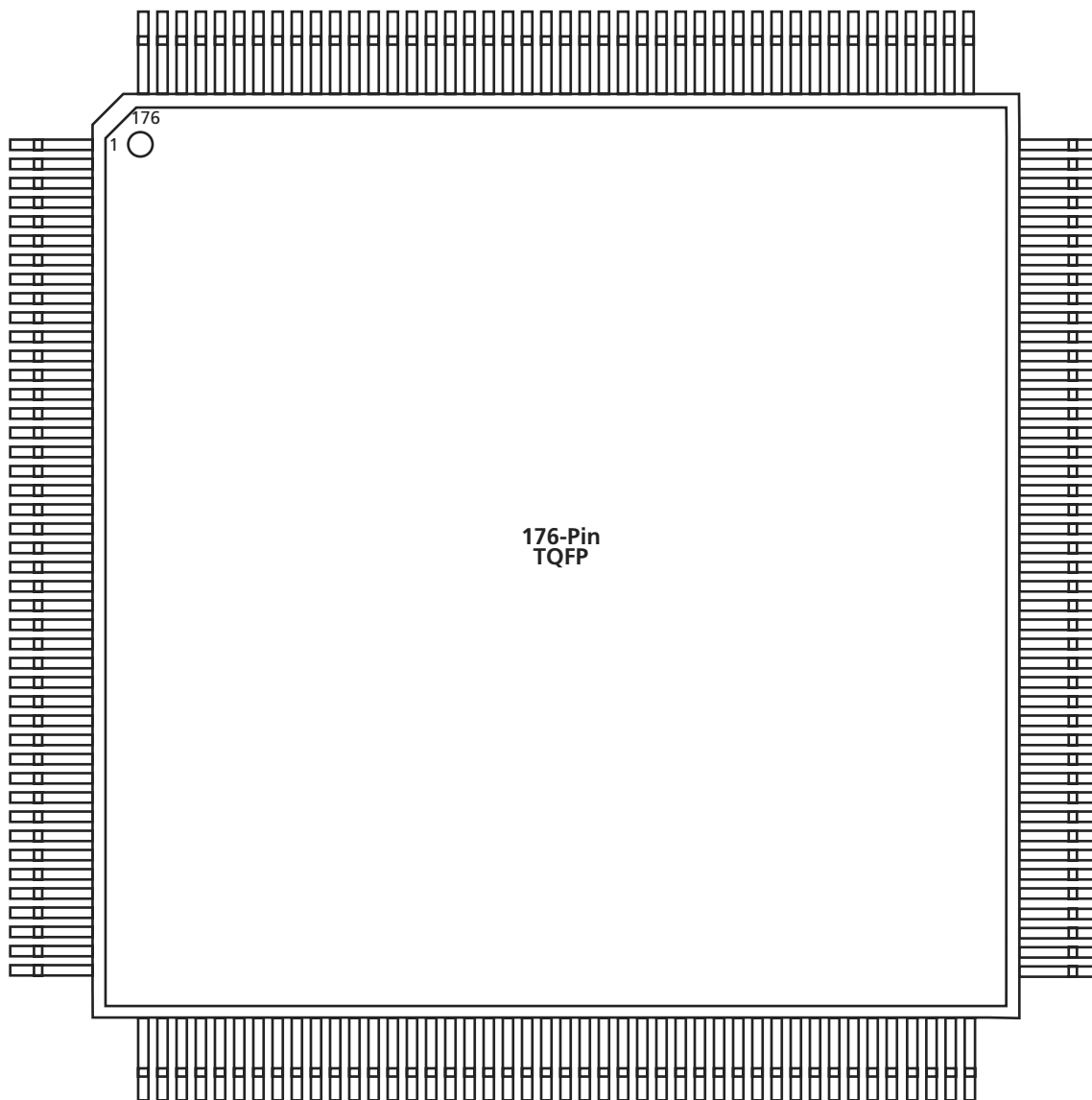


Figure 2-4 • 176-Pin TQFP (Top View)

Note

For Package Manufacturing and Environmental information, visit the Package Resource center at <http://www.actel.com/products/rescenter/package/index.html>.

313-Pin PBGA		313-Pin PBGA		313-Pin PBGA		313-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
A1	GND	AC5	I/O	B10	I/O	E15	I/O
A3	NC	AC7	I/O	B12	I/O	E17	I/O
A5	I/O	AC9	I/O	B14	I/O	E19	I/O
A7	I/O	AC11	I/O	B16	I/O	E21	I/O
A9	I/O	AC13	V _{CCR}	B18	I/O	E23	I/O
A11	I/O	AC15	I/O	B20	I/O	E25	I/O
A13	V _{CCR}	AC17	I/O	B22	I/O	F2	I/O
A15	I/O	AC19	I/O	B24	I/O	F4	I/O
A17	I/O	AC21	I/O	C1	TDI, I/O	F6	NC
A19	I/O	AC23	I/O	C3	I/O	F8	I/O
A21	I/O	AC25	NC	C5	NC	F10	NC
A23	NC	AD2	GND	C7	I/O	F12	I/O
A25	GND	AD4	I/O	C9	I/O	F14	I/O
AA1	I/O	AD6	V _{CCI}	C11	I/O	F16	NC
AA3	I/O	AD8	I/O	C13	V _{CCI}	F18	I/O
AA5	NC	AD10	I/O	C15	I/O	F20	I/O
AA7	I/O	AD12	PRB, I/O	C17	I/O	F22	I/O
AA9	NC	AD14	I/O	C19	V _{CCI}	F24	I/O
AA11	I/O	AD16	I/O	C21	I/O	G1	I/O
AA13	I/O	AD18	I/O	C23	I/O	G3	TMS
AA15	I/O	AD20	I/O	C25	NC	G5	I/O
AA17	I/O	AD22	NC	D2	I/O	G7	I/O
AA19	I/O	AD24	I/O	D4	NC	G9	V _{CCI}
AA21	I/O	AE1	NC	D6	I/O	G11	I/O
AA23	NC	AE3	I/O	D8	I/O	G13	CLKB
AA25	I/O	AE5	I/O	D10	I/O	G15	I/O
AB2	NC	AE7	I/O	D12	I/O	G17	I/O
AB4	NC	AE9	I/O	D14	I/O	G19	I/O
AB6	I/O	AE11	I/O	D16	I/O	G21	I/O
AB8	I/O	AE13	V _{CCA}	D18	I/O	G23	I/O
AB10	I/O	AE15	I/O	D20	I/O	G25	I/O
AB12	I/O	AE17	I/O	D22	I/O	H2	I/O
AB14	I/O	AE19	I/O	D24	NC	H4	I/O
AB16	I/O	AE21	I/O	E1	I/O	H6	I/O
AB18	V _{CCI}	AE23	TDO, I/O	E3	NC	H8	I/O
AB20	NC	AE25	GND	E5	I/O	H10	I/O
AB22	I/O	B2	TCK, I/O	E7	I/O	H12	PRA, I/O
AB24	I/O	B4	I/O	E9	I/O	H14	I/O
AC1	I/O	B6	I/O	E11	I/O	H16	I/O
AC3	I/O	B8	I/O	E13	V _{CCA}	H18	NC

313-Pin PBGA		313-Pin PBGA		313-Pin PBGA		313-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
H20	I/O	L25	I/O	R5	I/O	V10	I/O
H22	V _{CCI}	M2	I/O	R7	I/O	V12	I/O
H24	I/O	M4	I/O	R9	I/O	V14	I/O
J1	I/O	M6	I/O	R11	I/O	V16	NC
J3	I/O	M8	I/O	R13	GND	V18	I/O
J5	I/O	M10	I/O	R15	I/O	V20	I/O
J7	NC	M12	GND	R17	I/O	V22	V _{CCA}
J9	I/O	M14	GND	R19	I/O	V24	V _{CCI}
J11	I/O	M16	V _{CCI}	R21	I/O	W1	I/O
J13	CLKA	M18	I/O	R23	I/O	W3	I/O
J15	I/O	M20	I/O	R25	I/O	W5	I/O
J17	I/O	M22	I/O	T2	I/O	W7	NC
J19	I/O	M24	I/O	T4	I/O	W9	I/O
J21	GND	N1	I/O	T6	I/O	W11	I/O
J23	I/O	N3	V _{CCA}	T8	I/O	W13	V _{CCI}
J25	I/O	N5	V _{CCR}	T10	I/O	W15	I/O
K2	I/O	N7	I/O	T12	I/O	W17	I/O
K4	I/O	N9	V _{CCI}	T14	HCLK	W19	I/O
K6	I/O	N11	GND	T16	I/O	W21	I/O
K8	V _{CCI}	N13	GND	T18	I/O	W23	I/O
K10	I/O	N15	GND	T20	I/O	W25	I/O
K12	I/O	N17	I/O	T22	I/O	Y2	I/O
K14	I/O	N19	I/O	T24	I/O	Y4	I/O
K16	I/O	N21	I/O	U1	I/O	Y6	I/O
K18	I/O	N23	V _{CCR}	U3	I/O	Y8	I/O
K20	V _{CCA}	N25	V _{CCA}	U5	V _{CCI}	Y10	I/O
K22	I/O	P2	I/O	U7	I/O	Y12	I/O
K24	I/O	P4	I/O	U9	I/O	Y14	I/O
L1	I/O	P6	I/O	U11	I/O	Y16	I/O
L3	I/O	P8	I/O	U13	I/O	Y18	I/O
L5	I/O	P10	I/O	U15	I/O	Y20	NC
L7	I/O	P12	GND	U17	I/O	Y22	I/O
L9	I/O	P14	GND	U19	I/O	Y24	NC
L11	I/O	P16	I/O	U21	I/O		
L13	GND	P18	I/O	U23	I/O		
L15	I/O	P20	NC	U25	I/O		
L17	I/O	P22	I/O	V2	V _{CCA}		
L19	I/O	P24	I/O	V4	I/O		
L21	I/O	R1	I/O	V6	I/O		
L23	I/O	R3	I/O	V8	I/O		

329-Pin PBGA		329-Pin PBGA		329-Pin PBGA		329-Pin PBGA	
Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function	Pin Number	A54SX32 Function
A1	GND	AA13	I/O	AC2	V _{CCI}	B14	I/O
A2	GND	AA14	I/O	AC3	NC	B15	I/O
A3	V _{CCI}	AA15	I/O	AC4	I/O	B16	I/O
A4	NC	AA16	I/O	AC5	I/O	B17	I/O
A5	I/O	AA17	I/O	AC6	I/O	B18	I/O
A6	I/O	AA18	I/O	AC7	I/O	B19	I/O
A7	V _{CCI}	AA19	I/O	AC8	I/O	B20	I/O
A8	NC	AA20	TDO, I/O	AC9	V _{CCI}	B21	I/O
A9	I/O	AA21	V _{CCI}	AC10	I/O	B22	GND
A10	I/O	AA22	I/O	AC11	I/O	B23	V _{CCI}
A11	I/O	AA23	V _{CCI}	AC12	I/O	C1	NC
A12	I/O	AB1	I/O	AC13	I/O	C2	TDI, I/O
A13	CLKB	AB2	GND	AC14	I/O	C3	GND
A14	I/O	AB3	I/O	AC15	NC	C4	I/O
A15	I/O	AB4	I/O	AC16	I/O	C5	I/O
A16	I/O	AB5	I/O	AC17	I/O	C6	I/O
A17	I/O	AB6	I/O	AC18	I/O	C7	I/O
A18	I/O	AB7	I/O	AC19	I/O	C8	I/O
A19	I/O	AB8	I/O	AC20	I/O	C9	I/O
A20	I/O	AB9	I/O	AC21	NC	C10	I/O
A21	NC	AB10	I/O	AC22	V _{CCI}	C11	I/O
A22	V _{CCI}	AB11	PRB, I/O	AC23	GND	C12	I/O
A23	GND	AB12	I/O	B1	V _{CCI}	C13	I/O
AA1	V _{CCI}	AB13	HCLK	B2	GND	C14	I/O
AA2	I/O	AB14	I/O	B3	I/O	C15	I/O
AA3	GND	AB15	I/O	B4	I/O	C16	I/O
AA4	I/O	AB16	I/O	B5	I/O	C17	I/O
AA5	I/O	AB17	I/O	B6	I/O	C18	I/O
AA6	I/O	AB18	I/O	B7	I/O	C19	I/O
AA7	I/O	AB19	I/O	B8	I/O	C20	I/O
AA8	I/O	AB20	I/O	B9	I/O	C21	V _{CCI}
AA9	I/O	AB21	I/O	B10	I/O	C22	GND
AA10	I/O	AB22	GND	B11	I/O	C23	NC
AA11	I/O	AB23	I/O	B12	PRA, I/O	D1	I/O
AA12	I/O	AC1	GND	B13	CLKA	D2	I/O

329-Pin PBGA		329-Pin PBGA		329-Pin PBGA		329-Pin PBGA	
Pin Number	A545X32 Function	Pin Number	A545X32 Function	Pin Number	A545X32 Function	Pin Number	A545X32 Function
D3	I/O	F22	I/O	K20	I/O	N11	GND
D4	TCK, I/O	F23	I/O	K21	I/O	N12	GND
D5	I/O	G1	I/O	K22	I/O	N13	GND
D6	I/O	G2	I/O	K23	I/O	N14	GND
D7	I/O	G3	I/O	L1	I/O	N20	NC
D8	I/O	G4	I/O	L2	I/O	N21	I/O
D9	I/O	G20	I/O	L3	I/O	N22	I/O
D10	I/O	G21	I/O	L4	V _{CCR}	N23	I/O
D11	V _{CCA}	G22	I/O	L10	GND	P1	I/O
D12	V _{CCR}	G23	GND	L11	GND	P2	I/O
D13	I/O	H1	I/O	L12	GND	P3	I/O
D14	I/O	H2	I/O	L13	GND	P4	I/O
D15	I/O	H3	I/O	L14	GND	P10	GND
D16	I/O	H4	I/O	L20	V _{CCR}	P11	GND
D17	I/O	H20	V _{CCA}	L21	I/O	P12	GND
D18	I/O	H21	I/O	L22	I/O	P13	GND
D19	I/O	H22	I/O	L23	NC	P14	GND
D20	I/O	H23	I/O	M1	I/O	P20	I/O
D21	I/O	J1	NC	M2	I/O	P21	I/O
D22	I/O	J2	I/O	M3	I/O	P22	I/O
D23	I/O	J3	I/O	M4	V _{CCA}	P23	I/O
E1	V _{CCI}	J4	I/O	M10	GND	R1	I/O
E2	I/O	J20	I/O	M11	GND	R2	I/O
E3	I/O	J21	I/O	M12	GND	R3	I/O
E4	I/O	J22	I/O	M13	GND	R4	I/O
E20	I/O	J23	I/O	M14	GND	R20	I/O
E21	I/O	K1	I/O	M20	V _{CCA}	R21	I/O
E22	I/O	K2	I/O	M21	I/O	R22	I/O
E23	I/O	K3	I/O	M22	I/O	R23	I/O
F1	I/O	K4	I/O	M23	V _{CCI}	T1	I/O
F2	TMS	K10	GND	N1	I/O	T2	I/O
F3	I/O	K11	GND	N2	I/O	T3	I/O
F4	I/O	K12	GND	N3	I/O	T4	I/O
F20	I/O	K13	GND	N4	I/O	T20	I/O
F21	I/O	K14	GND	N10	GND	T21	I/O